

Notice of References Cited

Application/Control No.

09/777,076

Applicant(s)/Patent Under
Reexamination
STERN ET AL.

Examiner

Thien M. Le

Art Unit

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Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,587,577	12-1996	Schultz, Darald R.	235/462.44
	B	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ikeda et al., "Two dimensional miniature optical-scanning sensor with silicon micromachined scanning mirror", SPIE 3008, 111.
	V	Kiang et al., "Micromachined microscanners for optical scanning, SPIE 3008,82 (1997)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.